

Effects of  
AEA Cell-Bypass-Switch Closure  
on Charged EOS-Aqua NiH<sub>2</sub> Cell

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## Objectives

- Verify the Performance of AEA Cell Bypass Protection Device (CBPD) under simulated EOS- Aqua/Aura flight hardware configuration
- Assess the Safety of the hardware under an inadvertent firing of CBPD switch, as well as the closing of CBPD switch under simulated high cell impedance
- Confirm that the mode of operation of CBPD switch is the formation of a continuous low impedance path (a homogeneous low melting point alloy)



## EOS-Aqua Flight Hardware

- Battery Cells:
  - Eagle-Picher 160 Ah NiH<sub>2</sub> (RNH 160-3)
  - Size: ~ 12cm Diameter  
~ 32cm overall Height
  - Weight: ~ 4.3kg
- Cell-Bypass-Switch:
  - AEA Technology  
Cell Bypass Protection Device (CBPD)



## AEA Hardware Tested

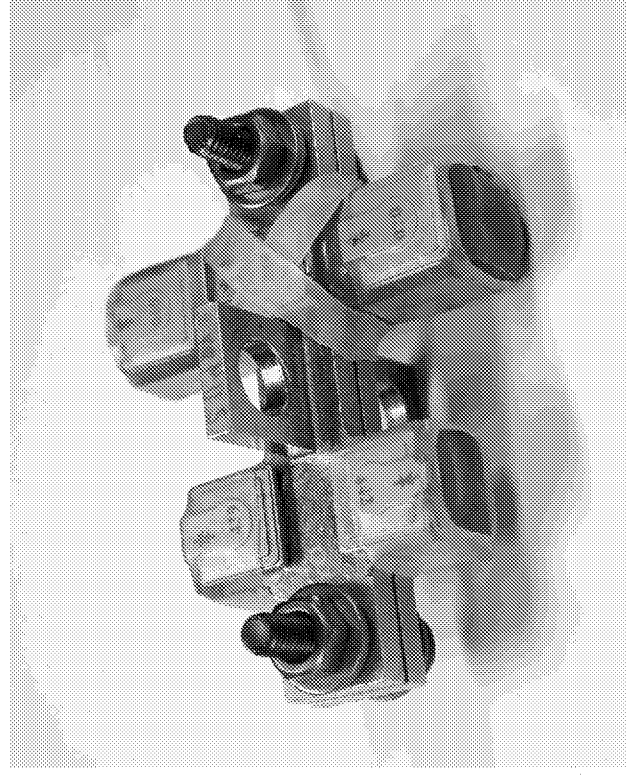
- A total of five (5) CBPDs were tested using the charged EOS Cell
  - Three FLIGHT devices (F01, F02 and F03)
  - Two ENGINEERING MODEL devices (EM01 & EM02)
- The two types of CBPDs are basically the same, with a change in separator and minor outer dimension changes



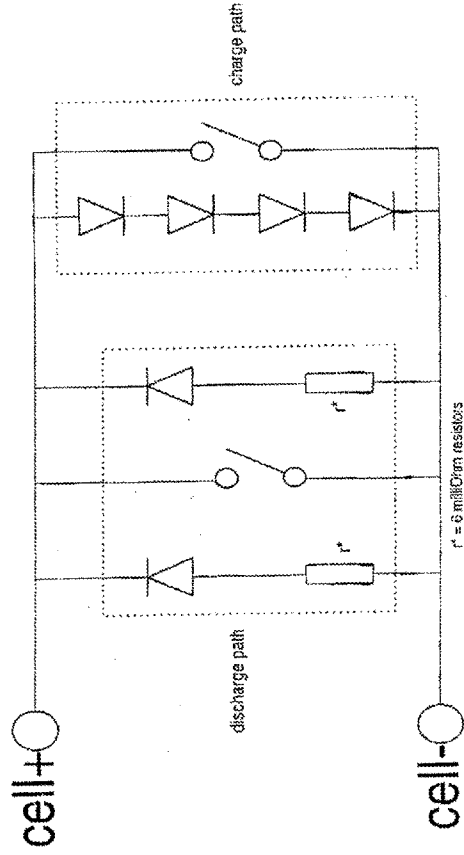
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# AEA Bypass Switch Schematic

**CBPD - LMPA Schematic**  
(Low Melting Point Alloy)



FLIGHT CBPD



Slide serial no 6  
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**NOTE:** Tested devices have 6 series diodes in charge path (not 4 as shown)



## AEA Cell-Bypass-Switch Spec

### TRW spec for Aqua

90 grams

Icharge ~ 75A

R ~ 500 microOhms

### **CBPD - Specification**

- 75 grams
- Icharge < 35A
- I discharge < 235A
- Triggering - see operation summary
- R ~ 200 microOhms
- I operation < 400A - dependent on leads and mounting



Slide serial no 13  
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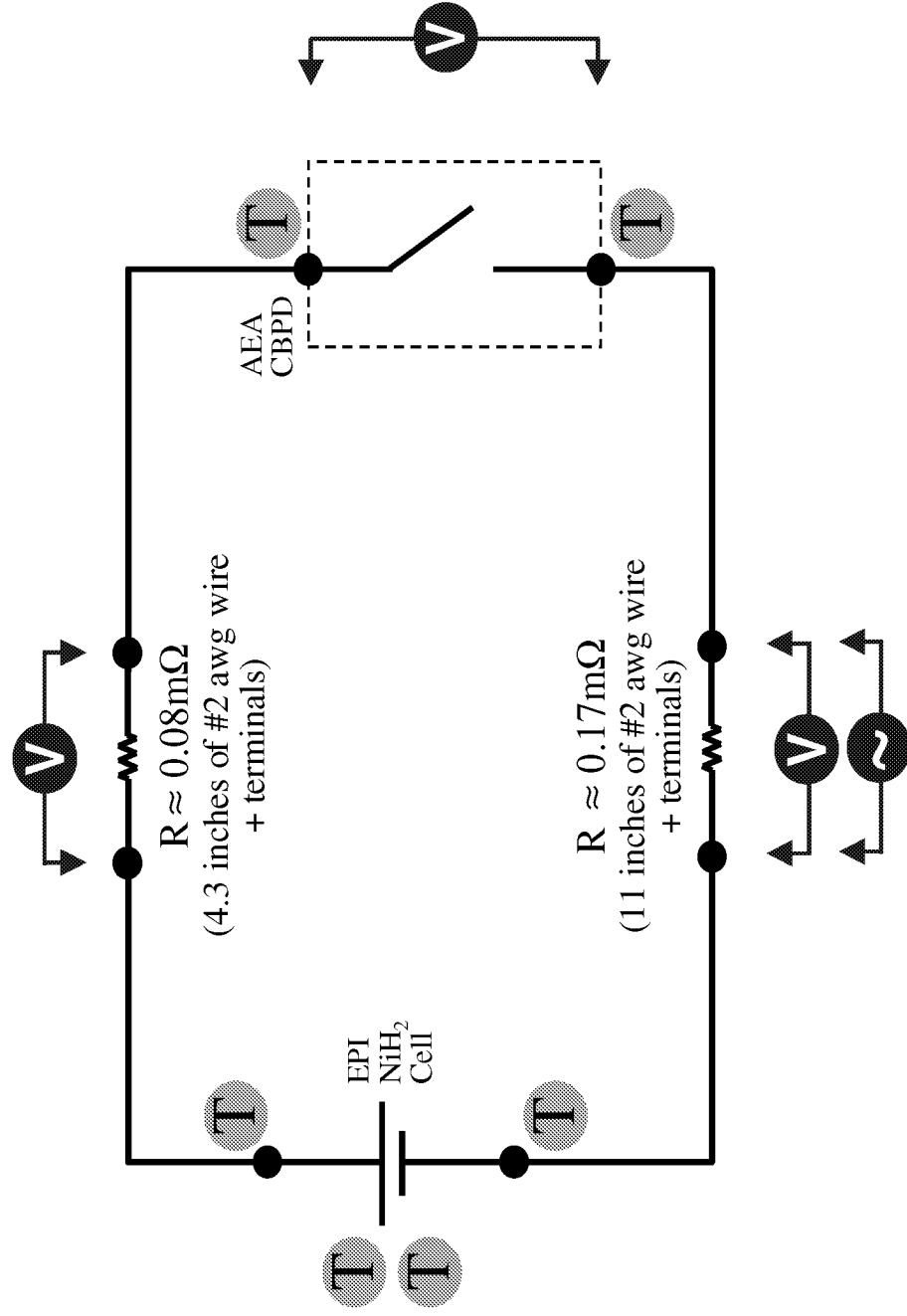


## Tests Performed

- **Test#1:**  
CBPD F01  
Activated with heatgun  
Switch-axis ~45° from Horizontal
- **Tests #2 & 3:**  
CBPD EM01 & EM02  
Activated through charge diodes  
Switch -axis Vertical
- **Test#4:**  
CBPD F02  
Activated through charge diodes  
Switch-axis Horizontal (launch orientation)
- **Test#5:**  
CBPD F03  
same as Test#4, with added 50 mΩ  
resistance in current path



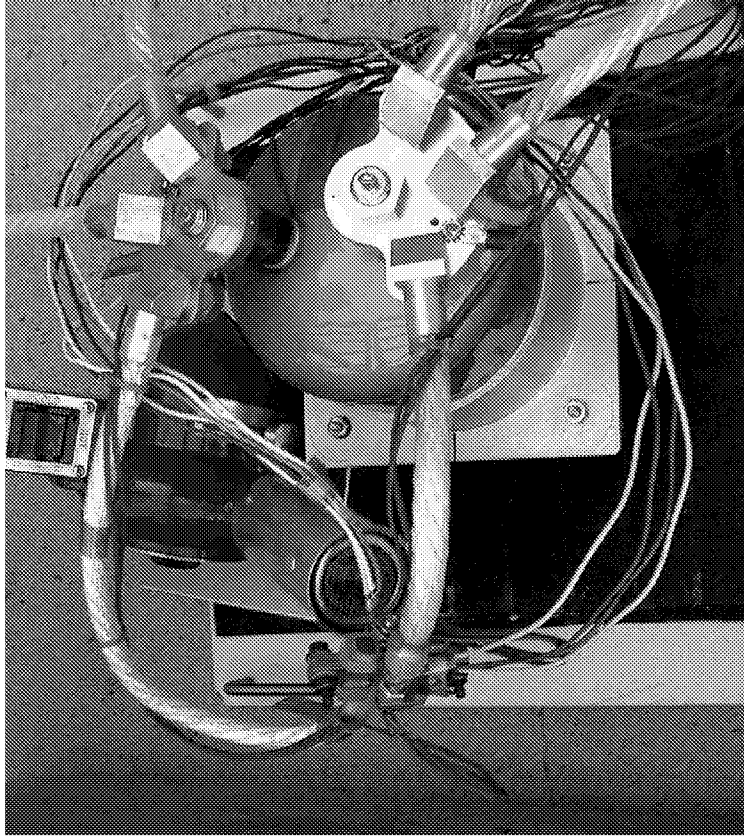
## Test #1 setup (switch activated with heatgun)



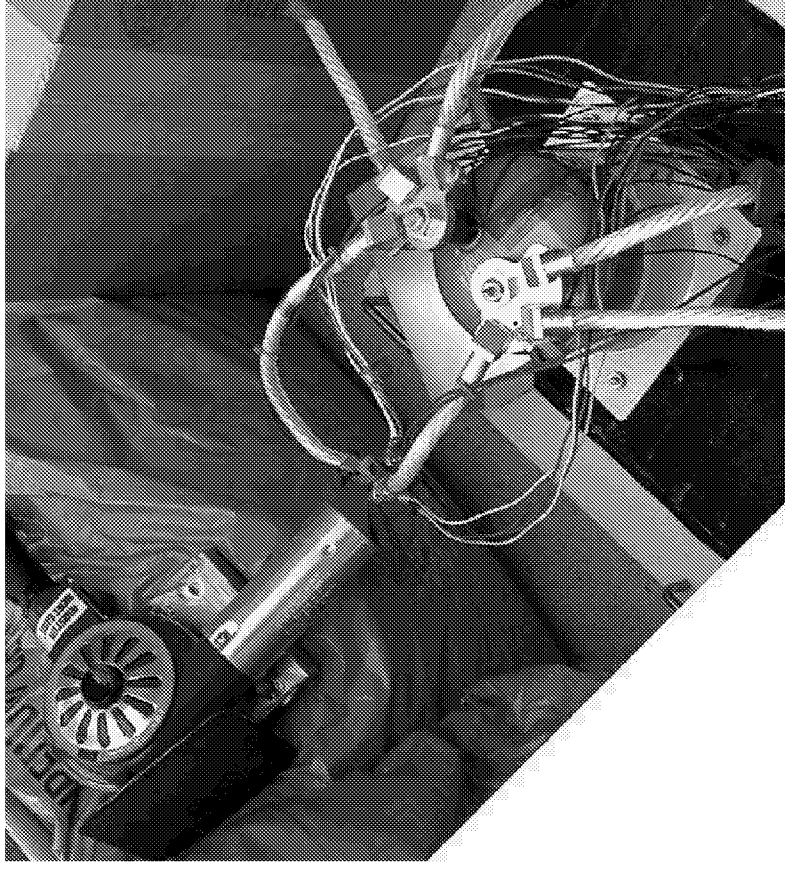




# Test #1



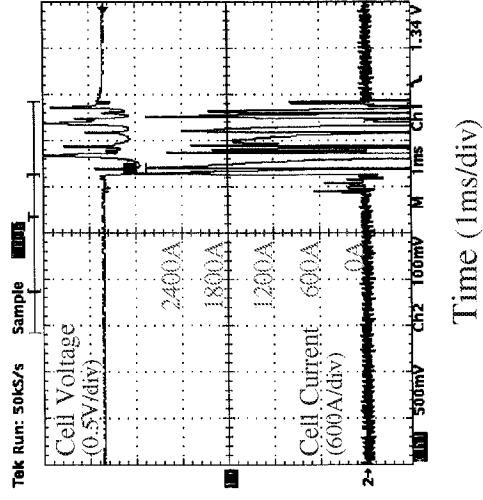
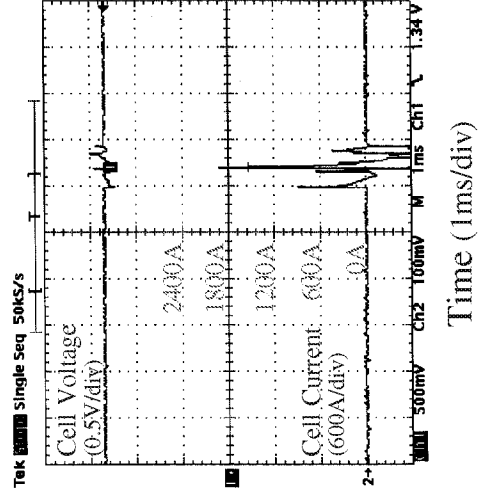
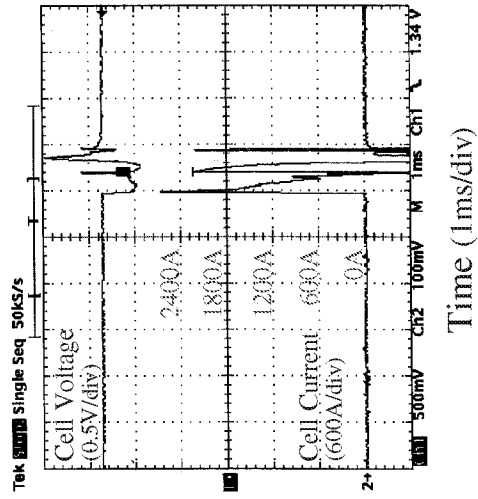
First application of heatgun



Heatgun repositioned for  
second application



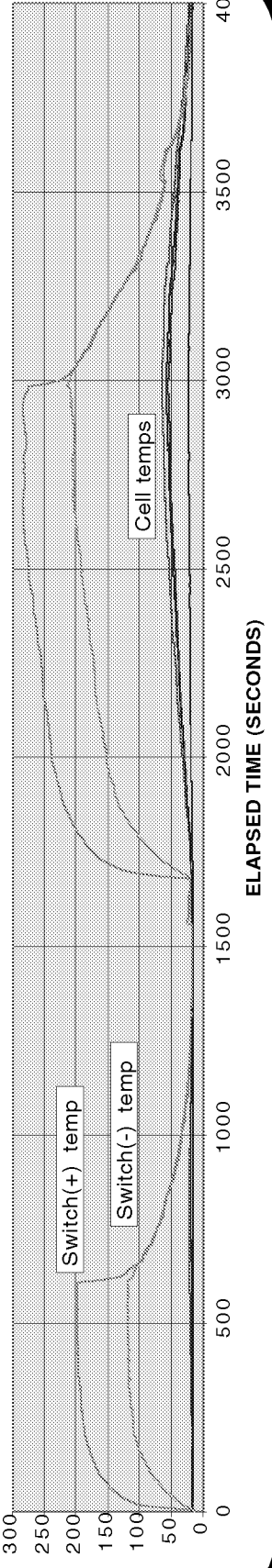
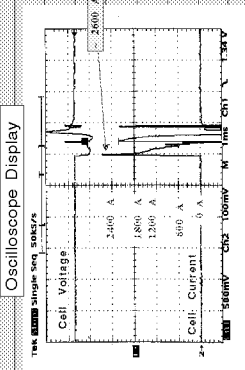
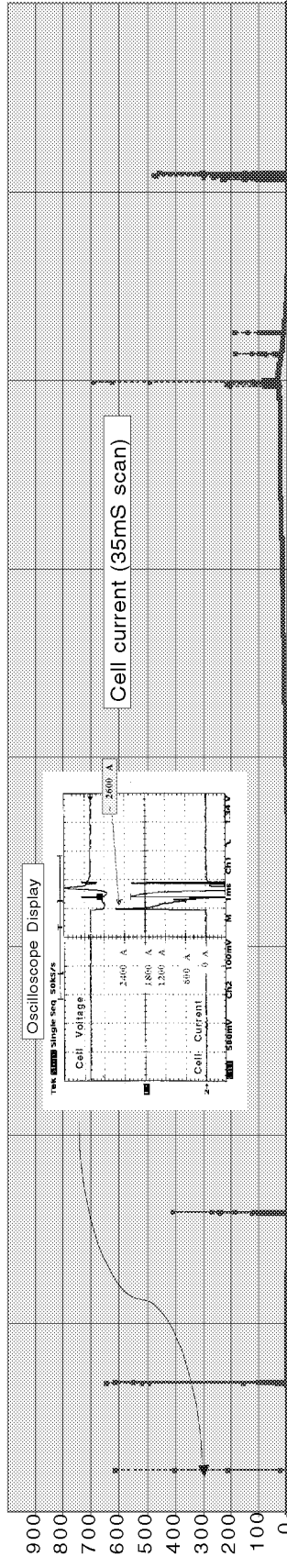
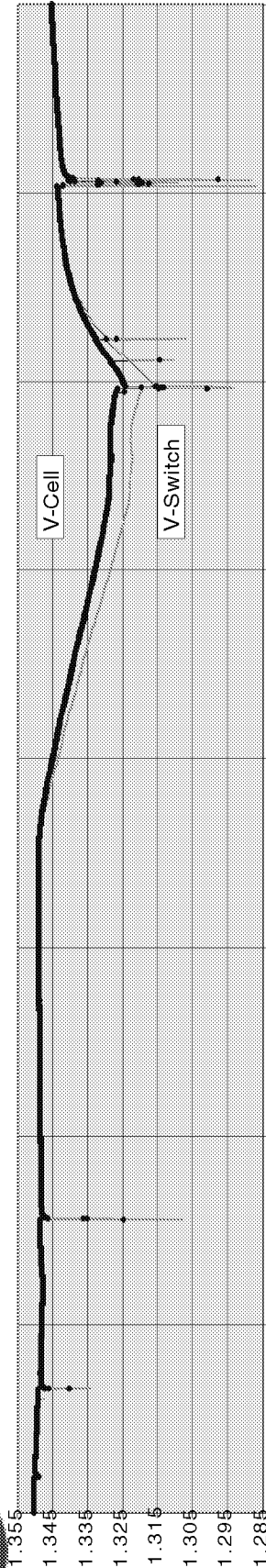
## Test #1 Scope Traces





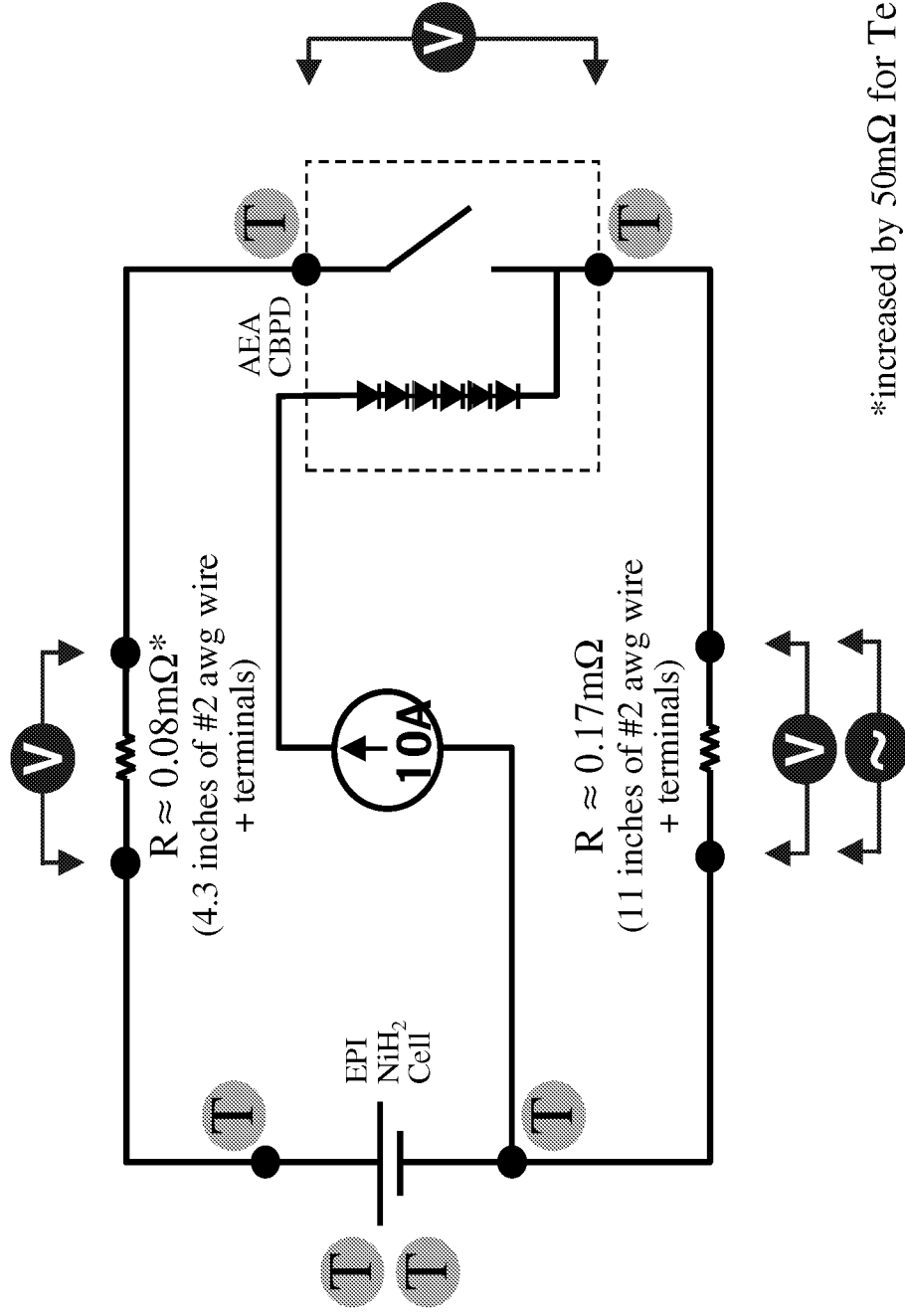
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## Test #1 Data



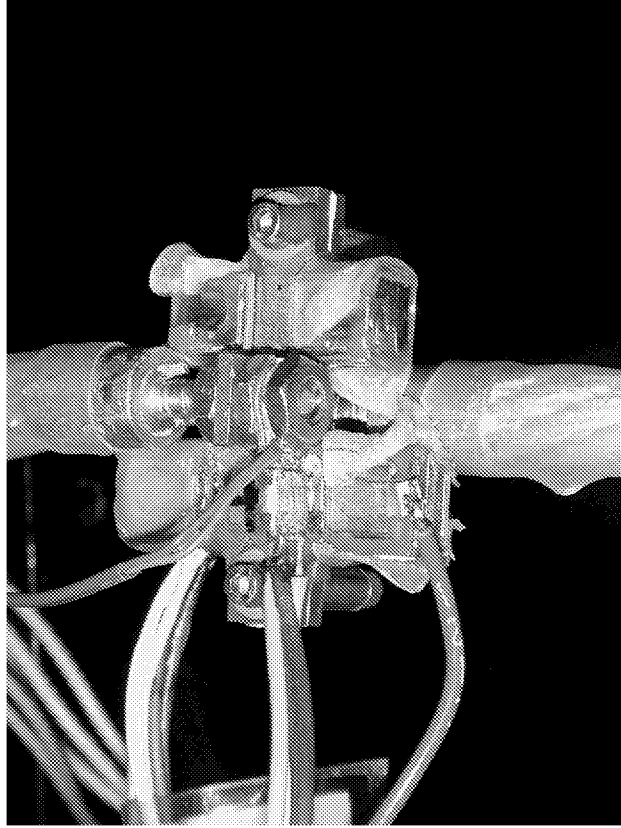


## Test #2 thru 5 setup (switch activated through diodes)

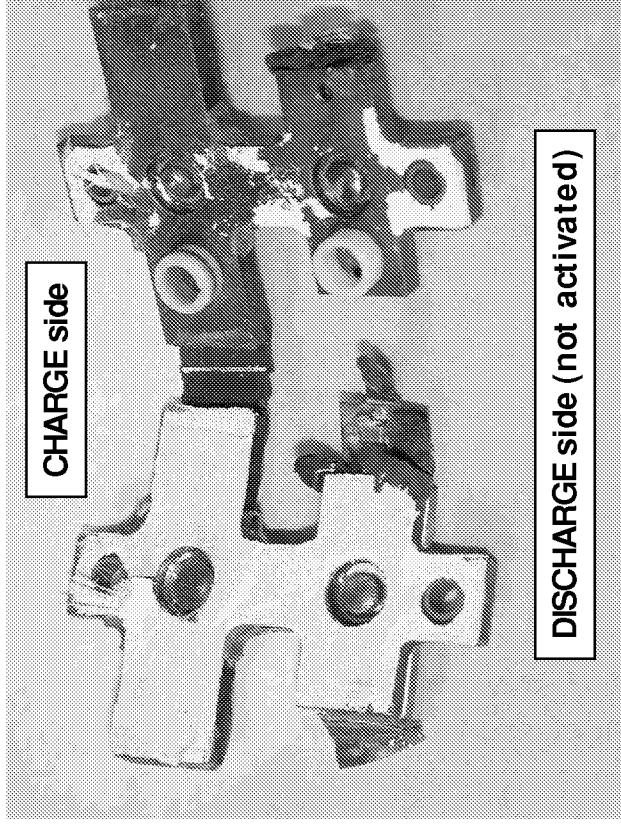




## Test #2



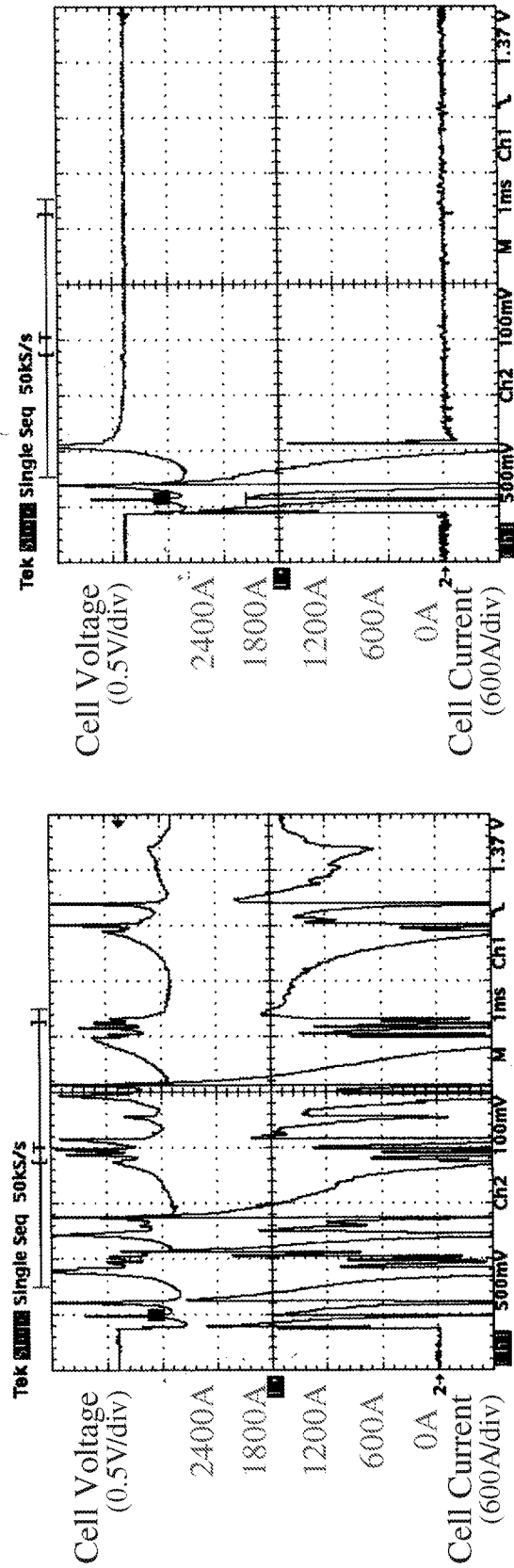
Engineering Model CBPD  
after test



CBPD opened after test.



## Test #2 & 3 Scope Traces

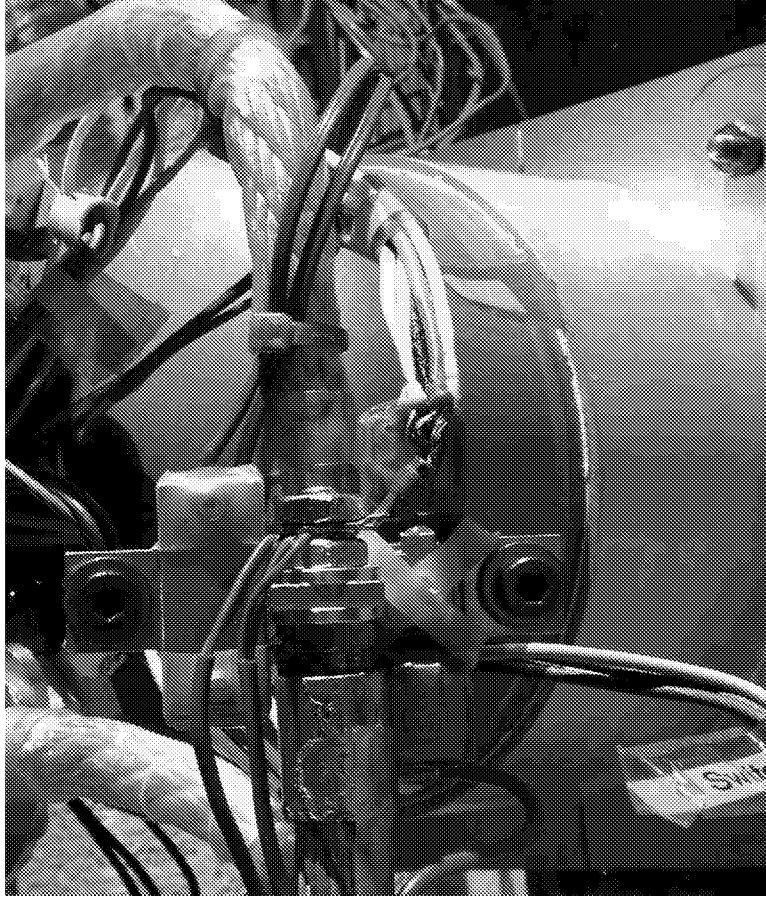


Time (1ms/div)

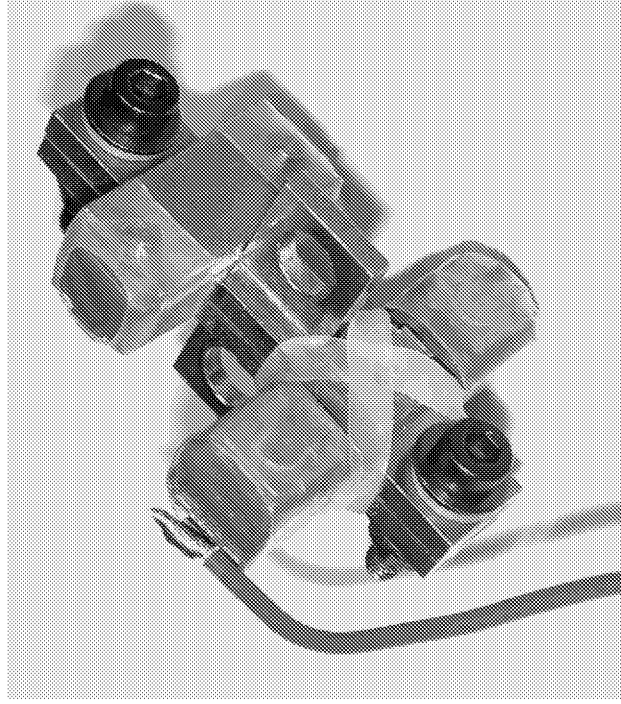
Time (1ms/div)



## Test #4



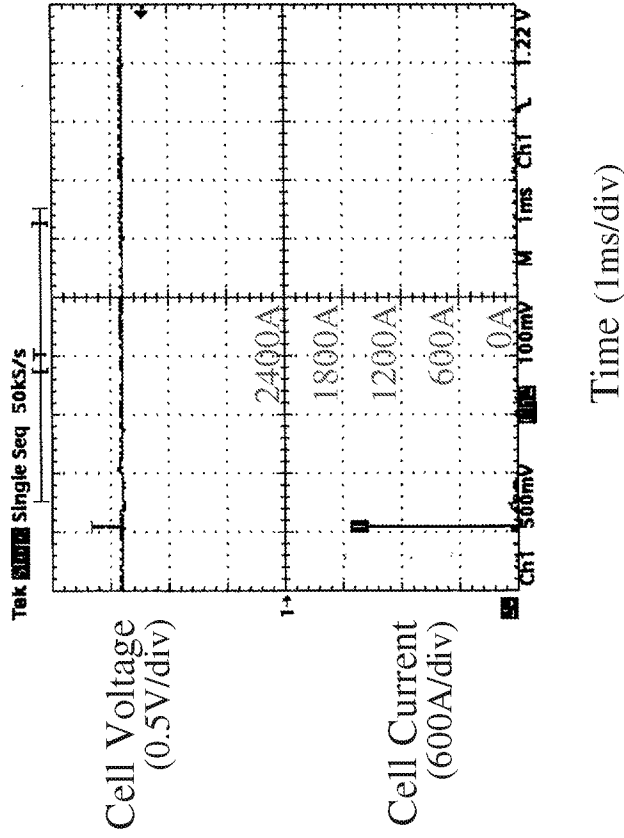
CBPD in launch orientation.



Charge diode string connection



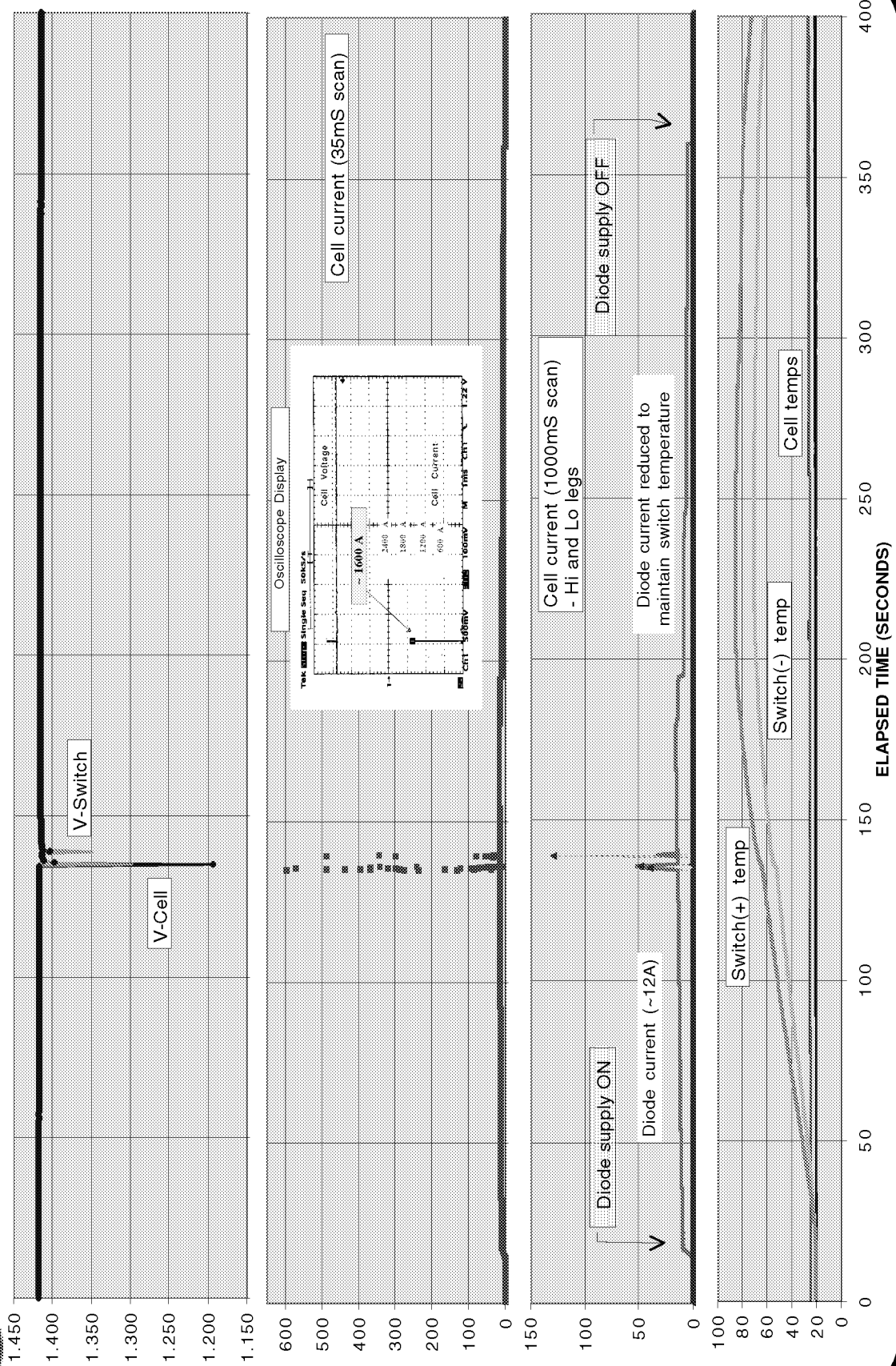
## Test #4 Scope Trace





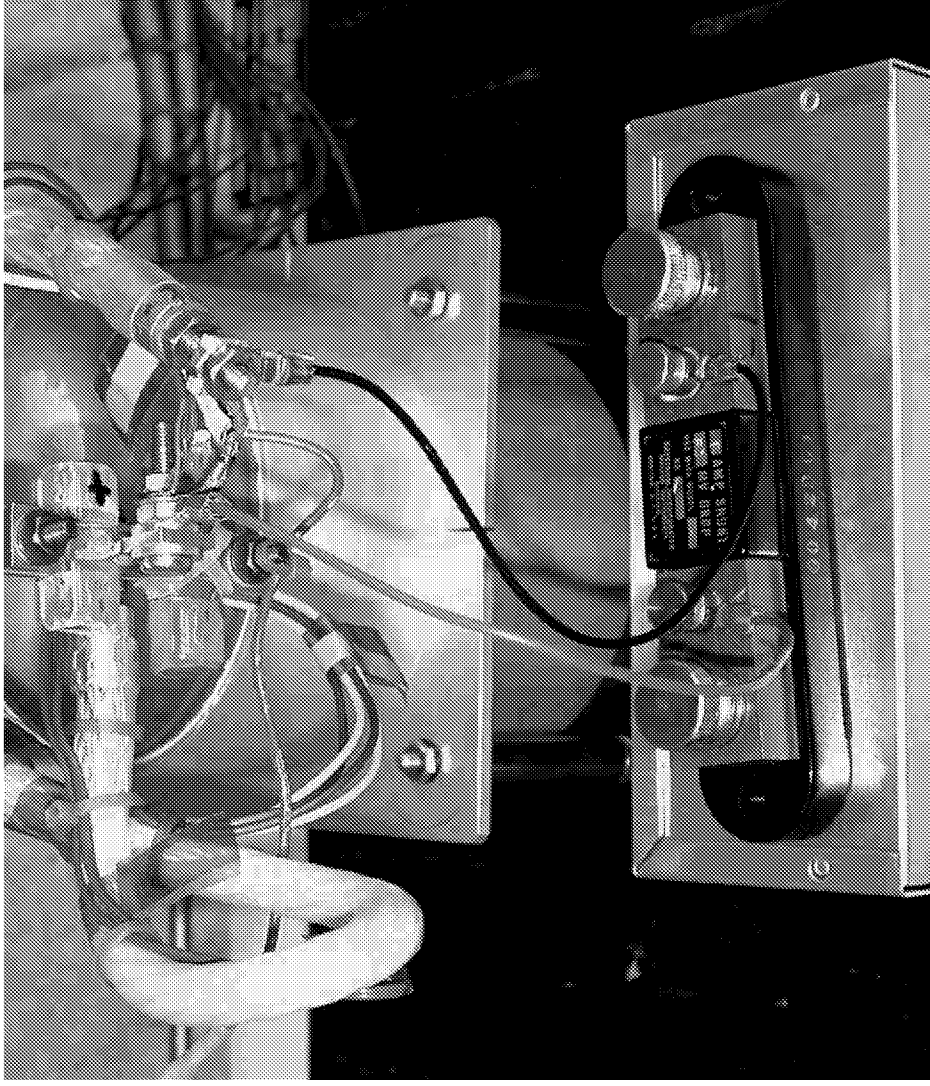


# Test #4 Data





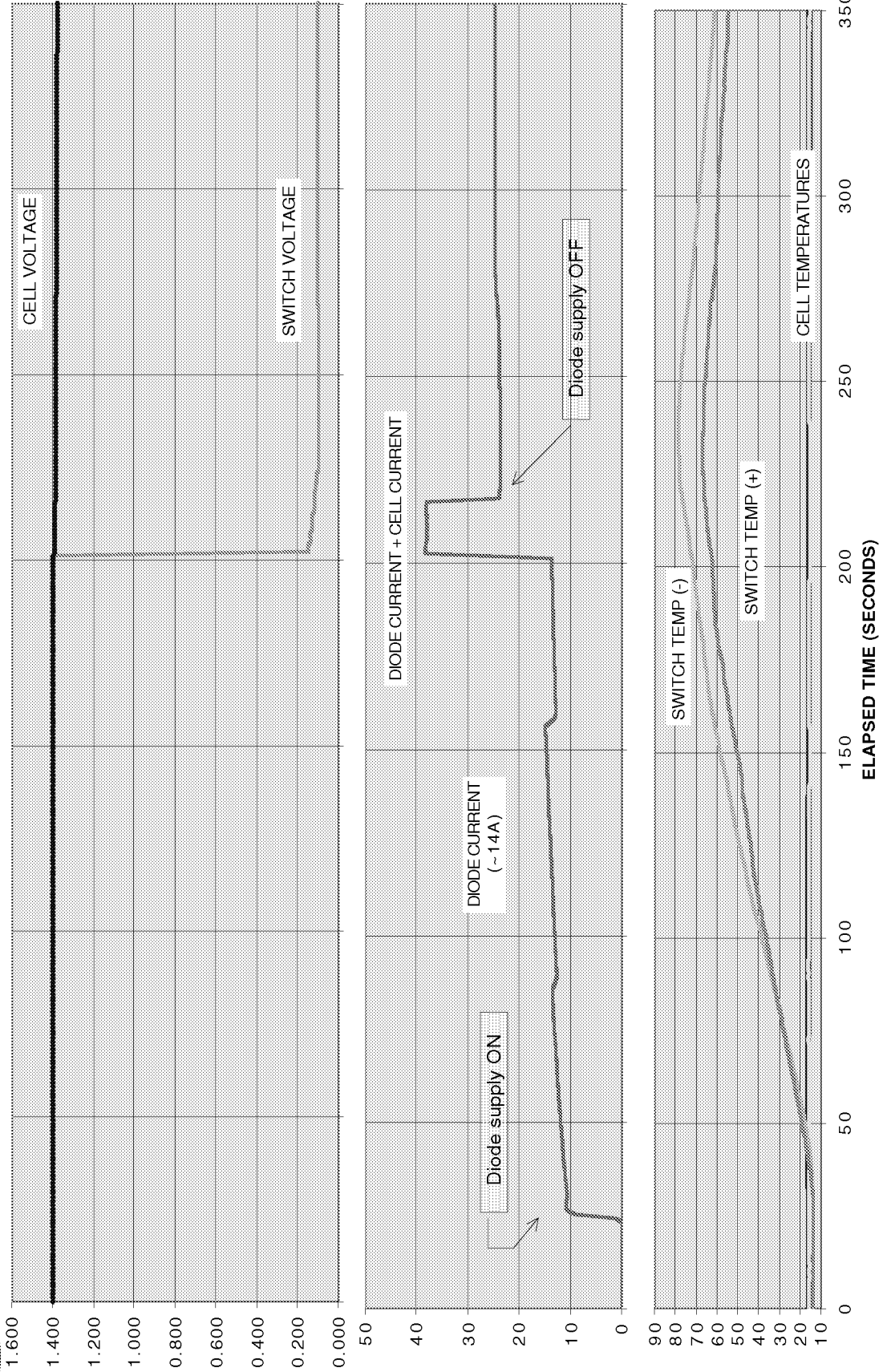
## Test #5



50 m $\Omega$  resistance added to positive current path



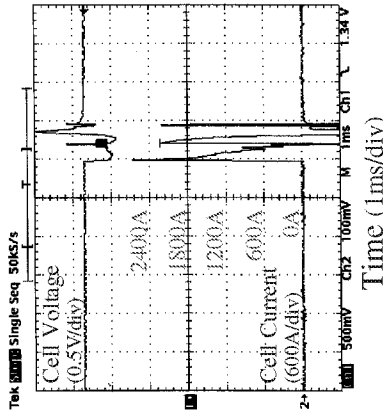
# Test #5 Data (with added 50mΩ)



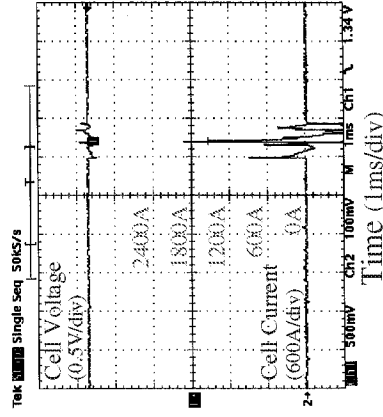


# Effects of AEA Cell-Bypass-Switch Closure on Charged EOS-Aqua NiH2 Cell

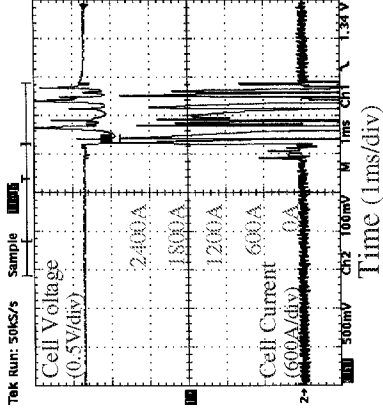
## Scope traces for Tests #1 thru 4



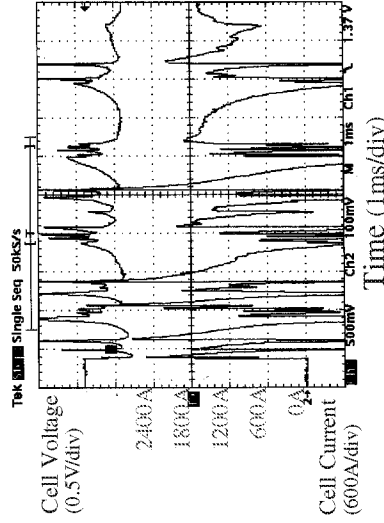
Test #1 (F01)



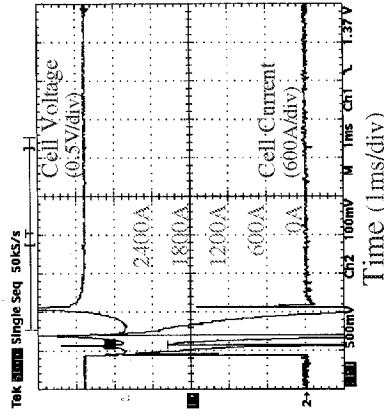
Test #1 (F02)



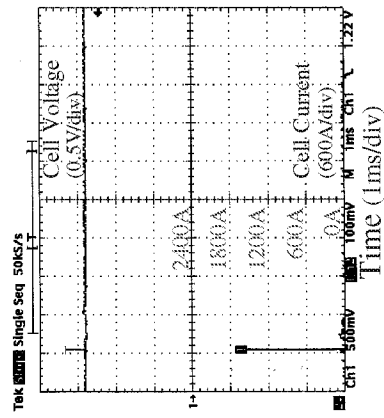
Test #1 (F03)



Test #2 (EM01)



Test #3 (EM02)



Test #4 (F02)



## Test Summary

Test #	CBPD #	Result
1	F01	<ul style="list-style-type: none"><li>- Seven distinct current bursts were recorded</li><li>- Switch failed to provide continuous short even after heating to near 300°C</li><li>- It is expected that both charge and discharge switches were activated by the high temperature</li></ul>
2	EM01	<ul style="list-style-type: none"><li>- One distinct current burst was recorded</li><li>- Switch failed to provide continuous short</li></ul>
3	EM02	<ul style="list-style-type: none"><li>- One distinct current burst was recorded</li><li>- Switch failed to provide continuous short</li></ul>
4	F02	<ul style="list-style-type: none"><li>- One distinct current burst was recorded</li><li>- Switch temperature was maintained over three minutes past the event, and switch still failed to provide continuous short</li></ul>
5	F03	<ul style="list-style-type: none"><li>- With 50 milliohms added to the current path, switch closed as expected, and maintained low impedance after diode current was removed and switch cooled</li></ul>



## Conclusions

- The nominal performance of AEA CBPD under simulated EOS-Aqua/Aura flight hardware configuration has been demonstrated.
- There is no evidence of cell rupture or excessive heat production during or after CBPD switch activation under simulated high cell impedance (open-circuit cell failure mode).
- Inadvertent CBPD switch activation with a charged cell (low impedance path) intermittently closes and opens up the switch, therefore the device may or may not provide protection against future open-circuit cell failure.  
Further testing with switches F01 and F02 may provide clarification.
- The formation of a continuous low impedance path (a homogeneous low melting point alloy), has been confirmed - which is the expected mode of operation.



## Further Work

- DPA of F03 (the only device to operate and carry continuous current) is in progress to confirm the formation of a stable, low impedance path
- Retest of F01 and F02 using added 50mΩ resistance is planned, with DPAs to follow



## Acknowledgements

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